

SPECIFICATION AMENDMENTS

Page 1, before BACKGROUND OF THE INVENTION, please add the following:

CROSS REFERENCE TO RELATED APPLICATIONS

This application is a continuation of serial no. 10/013,684, filed December 13, 2001, which is a continuation of serial no. 09/612,098, filed July 7, 2000, now patent no. 6,347,386, which in turn is a continuation of serial no. 09/150,289, filed September 9, 1998, now patent no. 6,128,756, which in turn is a continuation of serial no. 08/693,750, filed August 7, 1996, now patent no. 5,867,505, the disclosure of which is herewith incorporated by reference in its entirety.

COMPLETE LISTING OF CLAIMS

IN ASCENDING ORDER WITH STATUS INDICATOR

1. (Original) A method for testing a plurality of integrated circuits, including the steps of:

performing a plurality of tests on the plurality of integrated circuits;

identifying integrated circuits that failed at least one of the plurality of tests and identifying tests failed by the integrated circuits; and

repeating at least one identified failed test on the identified integrated circuits.

Claims 2-32. (Canceled)